

# NDT410EL

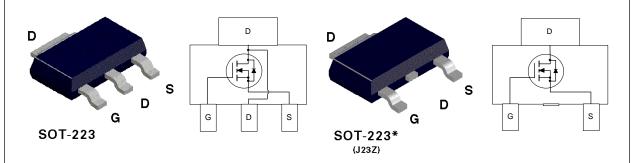
# N-Channel Logic Level Enhancement Mode Field Effect Transistor

# **General Description**

Power SOT N-Channel logic level enhancement mode power field effect transistors are produced using Fairchild's proprietary, high cell density, DMOS technology. This very high density process is especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulses in the avalanche and commutation modes. These devices are particularly suited for low voltage applications such as automotive, DC/DC converters, PWM motor controls, and other battery powered circuits where fast switching, low in-line power loss, and resistance to transients are needed.

#### **Features**

- $\blacksquare \quad \text{2.1A 100V. } \mathsf{R}_{\mathsf{DS}(\mathsf{ON})} = 0.25\Omega \quad @ \ \mathsf{V}_{\mathsf{GS}} = \mathsf{5V}.$
- High density cell design for extremely low R<sub>DS(ON)</sub>.
- High power and current handling capability in a widely used surface mount package.



# ABSOLUTE MAXIMUM RATINGS T<sub>a</sub> = 25°C unless otherwise noted

Symbol	Parameter		NDT410EL	Units
V <sub>DSS</sub>	Drain-Source Voltage		100	V
V <sub>GSS</sub>	Gate-Source Voltage		20	V
I <sub>D</sub>	Drain Current - Continuous	(Note 1a)	2.1	А
	- Pulsed		10	
P <sub>D</sub>	Maximum Power Dissipation	(Note 1a)	3	W
		(Note 1b)	1.3	
		(Note 1c)	1.1	
$T_J$ , $T_{STG}$	Operating and Storage Temperature Range	Э	-65 to 150	℃
THERMA	L CHARACTERISTICS			
R <sub>OJA</sub>	Thermal Resistance, Junction-to-Ambient	(Note 1a)	42	°CW
R <sub>OJC</sub>	Thermal Resistance, Junction-to-Case	(Note 1)	12	°CW

<sup>\*</sup> Order option J23Z for cropped center drain lead.

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Symbol	Parameter	Conditions	Min	Тур	Max	Units	
DRAIN-SC	DURCE AVALANCHE RATINGS (Note 2)						
W <sub>DSS</sub>	Single Pulse Drain-Source Avalanche En	ergy $V_{DD} = 50 \text{ V}, I_{D} = 10 \text{A}$			15	mJ	
I <sub>AR</sub>	Maximum Drain-Source Avalanche Curre	ent				10	Α
OFF CHA	RACTERISTICS						
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_{D} = 250 \mu\text{A}$	$V_{GS} = 0 \text{ V}, I_{D} = 250 \mu\text{A}$				V
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	$V_{DS} = 80 \text{ V}, \ V_{GS} = 0 \text{ V}$				1	μA
	T_= 55°C		T <sub>J</sub> = 55°C			10	μA
I <sub>GSSF</sub>	Gate - Body Leakage, Forward	$V_{GS} = 20 \text{ V}, V_{DS} = 0 \text{ V}$				100	nA
I <sub>GSSR</sub>	Gate - Body Leakage, Reverse	$V_{GS} = -20 \text{ V}, V_{DS} = 0 \text{ V}$					nA
ON CHAR	ACTERISTICS (Note 2)				•		•
V <sub>GS(th)</sub>	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu\text{A}$		1	1.5	2	V
			T <sub>J</sub> = 125°C	0.65	1.1	1.5	
R <sub>DS(ON)</sub>	Static Drain-Source On-Resistance	$V_{GS} = 5 \text{ V}, I_{D} = 2.1 \text{ A}$			0.2	0.25	Ω
			T <sub>J</sub> = 125°C		0.37	0.5	
I <sub>D(on)</sub>	On-State Drain Current	$V_{GS} = 5 \text{ V}, V_{DS} = 5 \text{ V}$	$V_{GS} = 5 \text{ V}, V_{DS} = 5 \text{ V}$				Α
g <sub>FS</sub>	Forward Transconductance	$V_{DS} = 10 \text{ V}, I_{D} = 2.1 \text{ A}$	$V_{DS} = 10 \text{ V}, I_{D} = 2.1 \text{ A}$				S
DYNAMIC	CHARACTERISTICS						
C <sub>iss</sub>	Input Capacitance	$V_{DS} = 25 \text{ V}, \ V_{GS} = 0 \text{ V},$	$V_{DS} = 25 \text{ V}, V_{GS} = 0 \text{ V},$				pF
C <sub>oss</sub>	Output Capacitance	f = 1.0 MHz			85		pF
C <sub>rss</sub>	Reverse Transfer Capacitance				20		pF
SWITCHIN	IG CHARACTERISTICS (Note 2)						
t <sub>D(on)</sub>	Turn - On Delay Time	$V_{DD} = 50 \text{ V}, I_D = 2.1 \text{ A},$	$V_{DD} = 50 \text{ V}, I_{D} = 2.1 \text{ A},$ $V_{GEN} = 5 \text{ V}, R_{GEN} = 25 \Omega$			20	ns
t,	Turn - On Rise Time	$V_{GEN} = 5 \text{ V}, R_{GEN} = 25 \Omega$				120	ns
t <sub>D(off)</sub>	Turn - Off Delay Time					80	ns
t,	Turn - Off Fall Time				47	80	ns
$Q_g$	Total Gate Charge	$V_{DS} = 80 \text{ V}, I_{D} = 2.1 \text{ A}, V_{GS} = 10.1 \text{ A}$	5 V		10	16	nC
$Q_{gs}$	Gate-Source Charge						nC
$Q_{gd}$	Gate-Drain Charge			5.6		nC	

ELECTRICAL CHARACTERISTICS (T <sub>A</sub> = 25°C unless otherwise noted)									
Symbol	Parameter Conditions Min Typ Max Un								
DRAIN-SOURCE DIODE CHARACTERISTICS AND MAXIMUM RATINGS									
Is	Maximum Continuous Drain-Source Diode Forward Current 2.3								
V <sub>SD</sub>	Drain-Source Diode Forward Voltage $V_{GS} = 0 \text{ V}, I_S = 2.3 \text{ A} \text{ (Note 2)}$				1.3	V			
t <sub>rr</sub>	Reverse Recovery Time	$V_{GS} = 0 \text{ V}, I_{S} = 2.3 \text{ A}, dI_{F}/dt = 100 \text{A/} \mu \text{s}$			150	ns			

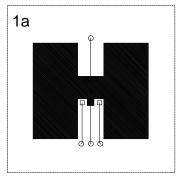
Notes:

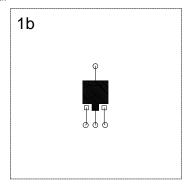
1.  $R_{\text{Bu,k}}$  is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins.  $R_{\text{Bu,c}}$  is guaranteed by design while  $R_{\text{gc,h}}$  is determined by the user's board design.  $P_D(t) = \frac{T_J - T_A}{R_{\text{Bu,k}}} = \frac{T_J - T_A}{R_{\text{Bu,k}}} = I_D^2(t) \times R_{DS(ON) \oplus T_J}$ Typical  $R_{\text{Bu,h}}$  using the board layouts shown below on 4.5°x5° FR-4 PCB in a still air environment:

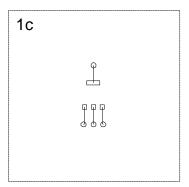
a. 42°C/W when mounted on a 1 in² pad of 2oz copper.

b. 95°C/W when mounted on a 0.04 in² pad of 2oz copper.

c. 110°C/W when mounted on a 0.006 in² pad of 2oz copper.







Scale 1 : 1 on letter size paper

2. Pulse Test: Pulse Width  $\leq$  300 $\mu$ s, Duty Cycle  $\leq$  2.0%.



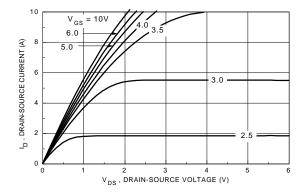


Figure 1. On-Region Characteristics.

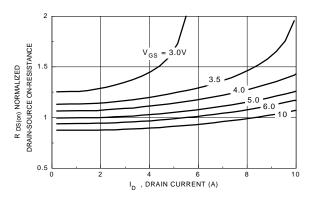


Figure 2. On-Resistance Variation with Gate Voltage and Drain Current.

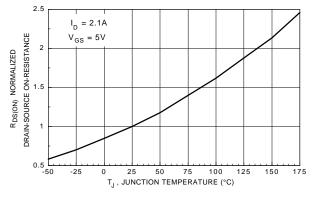


Figure 3. On-Resistance Variation with Temperature.

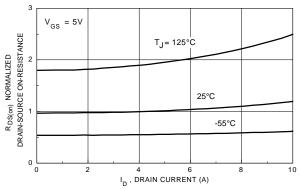


Figure 4. On-Resistance Variation with Drain Current and Temperature.

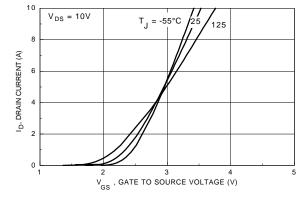


Figure 5. Transfer Characteristics.

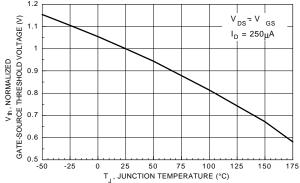


Figure 6. Gate Threshold Variation with Temperature.

# Typical Electrical Characteristics (continued)

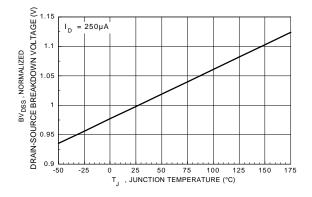


Figure 7. Breakdown Voltage Variation with Temperature.

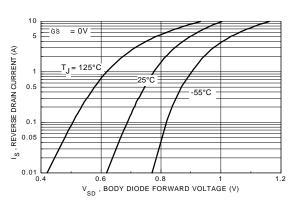


Figure 8. Body Diode Forward Voltage
Variation with Current and Temperature.

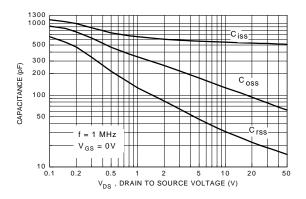


Figure 9. Capacitance Characteristics.

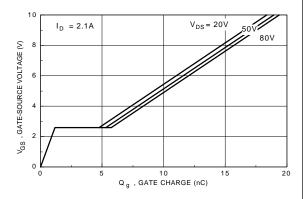


Figure 10. Gate Charge Characteristics.

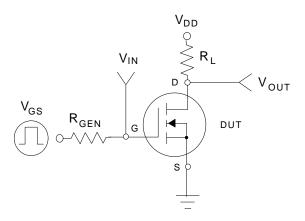


Figure 11. Switching Test Circuit.

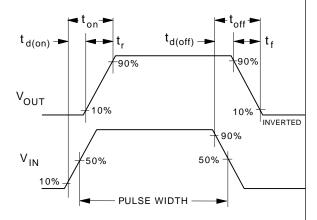


Figure 12. Switching Waveforms.

# **Typical Electrical and Thermal Characteristics**

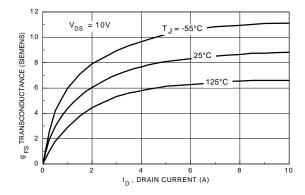
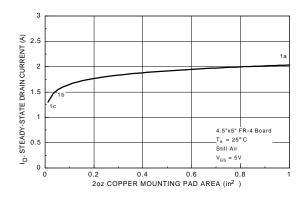


Figure 13. Transconductance Variation with Drain Current and Temperature.

Figure 14. SOT-223 Maximum Steady- State Power
Dissipation versus Copper Mounting Pad Area.



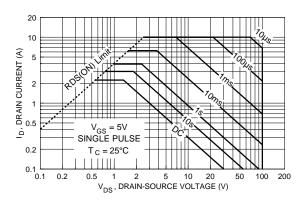


Figure 15. Maximum Steady-State Drain Current versus Copper Mounting Pad Area.

Figure 16. Maximum Safe Operating Area.

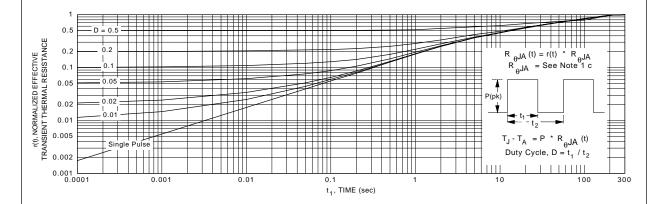
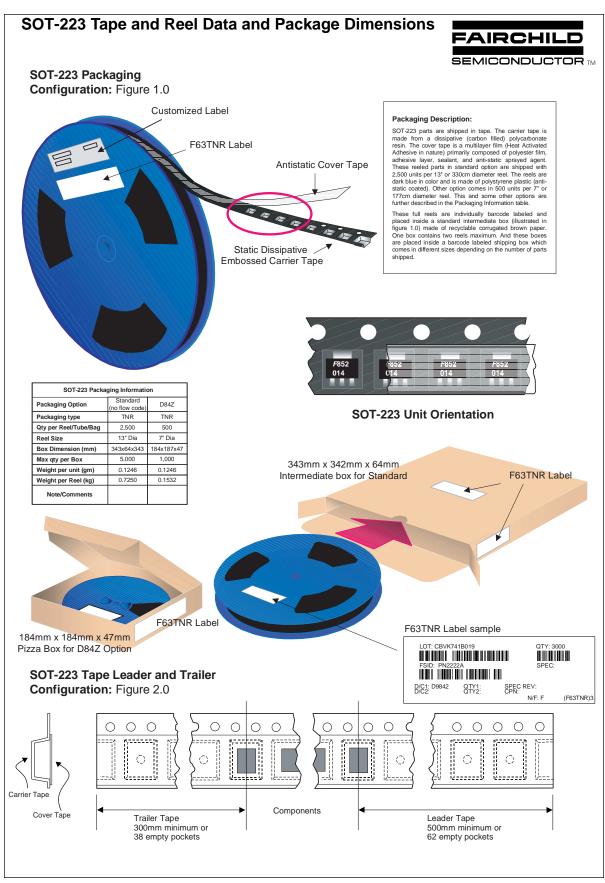
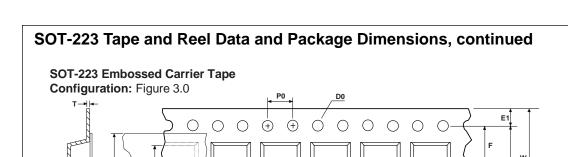


Figure 17. Transient Thermal Response Curve.

Note: Thermal characterization performed using the conditions described in note 1c. Transient thermal response will change depending on the circuit board design.





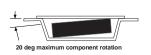


D1

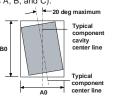
	Dimensions are in millimeter													
Pkg type	Α0	В0	w	D0	D1	E1	E2	F	P1	P0	K0	Т	Wc	Тс
<b>SOT-223</b> (12mm)	6.83 +/-0.10	7.42 +/-0.10	12.0 +/-0.3	1.55 +/-0.05	1.50 +/-0.10	1.75 +/-0.10	10.25 min	5.50 +/-0.05	8.0 +/-0.1	4.0 +/-0.1	1.88 +/-0.10	0.292 +/- 0.0130	9.5 +/-0.025	0.06 +/-0.02

Notes: A0, B0, and K0 dimensions are determined with respect to the EIA/Jedec RS-481 rotational and lateral movement requirements (see sketches A, B, and C).

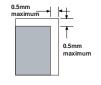
A0



Sketch A (Side or Front Sectional View)
Component Rotation

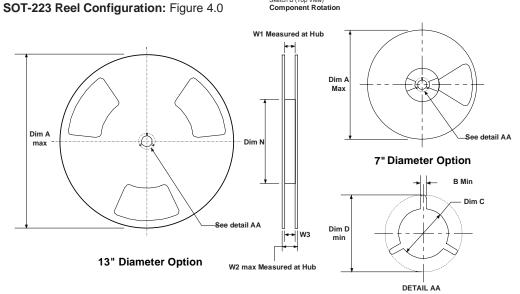


Sketch B (Top View)
Component Rotation



Sketch C (Top View)

Component lateral movement

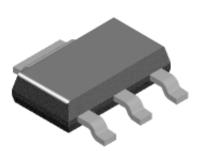


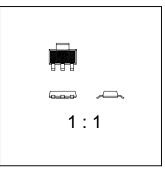
	Dimensions are in inches and millimeters								
Tape Size	Reel Option	Dim A	Dim B	Dim C	Dim D	Dim N	Dim W1	Dim W2	Dim W3 (LSL-USL)
12mm	7" Dia	7.00 177.8	0.059 1.5	512 +0.020/-0.008 13 +0.5/-0.2	0.795 20.2	5.906 150	0.488 +0.078/-0.000 12.4 +2/0	0.724 18.4	0.469 - 0.606 11.9 - 15.4
12mm	13" Dia	13.00 330	0.059 1.5	512 +0.020/-0.008 13 +0.5/-0.2	0.795 20.2	7.00 178	0.488 +0.078/-0.000 12.4 +2/0	0.724 18.4	0.469 - 0.606 11.9 - 15.4

July 1999, Rev. B

# SOT-223 Tape and Reel Data and Package Dimensions, continued

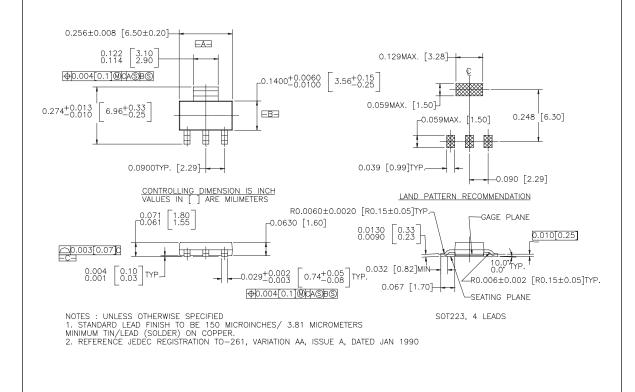
# SOT-223 (FS PKG Code 47)





Scale 1:1 on letter size paper

Part Weight per unit (gram): 0.1246



September 1999, Rev. C

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Datasheet Identification	Product Status	Definition
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